

Proceedings

The Second IEEE International Conference on Secure System Integration and Reliability Improvement

*Yokohama, Japan
July 14-17, 2008*

Co-Sponsored by

The IEEE Reliability Society
The IEEE Systems, Man, and Cybernetics Society



Los Alamitos, California
Washington • Tokyo



The Second International Conference on Secure System Integration and Reliability Improvement

SSIRI 2008

Table of Contents

Welcome Message from the General Chair.....	x
Welcome Message from the Program Chair.....	xi
Message from the Founding Chair.....	xii
Organizing Committee.....	xiii
Program Committee.....	xv
Keynote Abstracts.....	xvi
SSIRI 2008 Final Program.....	xix

Regular Papers

Security (1)

Vulnerability Analysis of HD Photo Image Viewer Applications	1
<i>Clifford C. Juan, James Bret Michael, and Christopher S. Eagle</i>	
A Pollution Attack Resistant Multicast Authentication Scheme Tolerant to Packet Loss	8
<i>Warren W. Lin, Shihpyng Shieh, and Jia-Chun Lin</i>	
Evaluation of Power-Constant Dual-Rail Logic as a Protection of Cryptographic Applications in FPGAs	16
<i>Sylvain Guilley, Laurent Sauvage, Jean-Luc Danger, Tarik Graba, and Yves Mathieu</i>	

Testing (1)

An Experimental Evaluation of the Reliability of Adaptive Random Testing Methods	24
<i>Yu Liu and Hong Zhu</i>	
Pairwise Testing in the Presence of Configuration Change Cost	32
<i>Shin Kimoto, Tatsuhiro Tsuchiya, and Tohru Kikuno</i>	
Historical Value-Based Approach for Cost-Cognizant Test Case Prioritization to Improve the Effectiveness of Regression Testing	39
<i>Hyuncheol Park, Hoyeon Ryu, and Jongmoon Baik</i>	

Reliability (1)

Validating UML Statechart-Based Assertions Libraries for Improved Reliability and Assurance	47
<i>Doron Drusinsky, James Bret Michael, Thomas W. Otani, and Man-Tak Shing</i>	
Ensuring Reliability and Availability of Soft System Bus	52
<i>Mohammad Reza Selim, Yuichi Goto, and Jingde Cheng</i>	
A Method of Reliability Assessment Based on Deterministic Chaos Theory for an Open Source Software	60
<i>Yoshinobu Tamura and Shigeru Yamada</i>	

Real-Time and Embedded Systems

Reliability Improvement of Real-Time Embedded System Using Checkpointing	67
<i>Sang-Moon Ryu</i>	
Dynamic Performance Analysis for Software System Considering Real-Time Property in Case of NHPP Task Arrival	73
<i>Koichi Tokuno and Shigeru Yamada</i>	
Shortening Test Case Execution Time for Embedded Software	81
<i>Valdivino Santiago, Wendell P. Silva, and N.L. Vijaykumar</i>	

Security (2)

A Blind Watermarking Scheme Based on Wavelet Tree Quantization	89
<i>Wei-Hung Lin, Yuh-Rau Wang, and Shi-Jinn Horng</i>	
Lightweight, Distributed Key Agreement Protocol for Wireless Sensor Networks	96
<i>Che-Cheng Lin, Shiuhyng Shieh, and Jia-Chun Lin</i>	

Automation and Product Lifetime

Automated Fault Diagnosis in Embedded Systems	103
<i>Peter Zoetewij, Jurryt Pietersma, Rui Abreu, Alexander Feldman, and Arjan J.C. van Gemund</i>	
Two Methods for Estimating Product Lifetimes from only Warranty Claims Data	111
<i>Kazuyuki Suzuki, Mesbahul Alam, Takuji Yoshikawa, and Wataru Yamamoto</i>	
Adaptive Car Plate Recognition in QoS-Aware Security Network	120
<i>Pei-Chen Tseng, Jiun-Kuei Shiung, Chun-Ting Huang, Shih-Mine Guo, and Wen-Shyang Hwang</i>	

Testing (2)

GUI Test Script Organization with Component Abstraction	128
<i>Woei-Kae Chen, Zheng-Wen Shen, and Che-Ming Chang</i>	
Which Spot Should I Test for Effective Embedded Software Testing?	135
<i>Jooyoung Seo, Yuhoon Ki, Byoungju Choi, and Kwanghyun La</i>	
FPGA-Based Fault Injection into Synthesizable Verilog HDL Models	143
<i>Mohammad Shokrolah-Shirazi and Seyed Ghassem Miremadi</i>	

Reliability (2)

Two-Dimensional Software Reliability Assessment with Testing-Coverage	150
<i>Shinji Inoue and Shigeru Yamada</i>	
A Study of Estimation for the Three-Parameter Weibull Distribution Based on Doubly Type-II Censored Data Using a Least Squares Method	158
<i>Hideki Nagatsuka</i>	
Proposal for a Communication Link Model Based on Resonance Frequency of Network Users	166
<i>Masato Uwajima, Toru Sasaki, Chisa Takano, and Masaki Aida</i>	

Fast Abstracts

Fast Abstract (1)

Towards an Interface causing Discomfort for Security: A User Survey on the Factors of Discomfort	173
<i>Yasuhiro Fujihara, Hitomi Oikawa, and Yuko Murayama</i>	
Improving Software Integration from Requirement Process with a Model-Based Object-Oriented Approach	175
<i>Chih-Hung Chang, Chih-Wei Lu, and William C. Chu</i>	
An Enhanced Model for Early Software Reliability Prediction Using Software Engineering Metrics	177
<i>K. Saravana Kumar and R.B. Misra</i>	

Application to Artificial Hip Stem Design of an Emergent Design System Applicable in the Early Process of Design	179
<i>Koichiro Sato, Yoshiki Ujiie, and Yoshiyuki Matsuoka</i>	
Application of Design for Six Sigma in Third Party Intensive Programs	181
<i>Subramanyam Ranganathan and Cvetan Redzic</i>	
Risk-Driven Software Reliability and Testing	183
<i>Norm Schneidewind and Mike Hinchey</i>	

Fast Abstract (2)

A Model of Bug Dynamics for Open Source Software	185
<i>Fengzhong Zou and Joseph Davis</i>	
Co-Simulation of Networked Embedded System: Verification Approach	187
<i>Nikhil Damle and A.G. Keskar</i>	
Text Extraction in Video Images	189
<i>Shwu-Huey Yen, Chun-Wei Wang, Jih-Pin Yeh, Meng-Ju Lin, and Hwei-Jen Lin</i>	
A Study of Visibility Evaluation for the Combination of Character Color and Background Color on a Web Page	191
<i>Nobuyuki Nishiuchi, Kimihiro Yamanaka, and Kunie Beppu</i>	
An Ant Colony Optimization Approach to Multi-Objective Supply Chain Model	193
<i>Ruoying Sun, Xingfen Wang, and Gang Zhao</i>	
Development of Fuzzy Software Operational Profile	195
<i>K. Saravana Kumar, Ravindra Babu Misra, and Neeraj Kumar Goyal</i>	
Effect of Creep Properties on Pressure Induced Tin Whisker Formation	197
<i>Tadahiro Shibutani, Qiang Yu, and Masaki Shiratori</i>	

Fast Abstract (3)

Design of Experiments is the "Sweet Spot" of Six Sigma	199
<i>Samuel Keene</i>	
Verifiable Aspect Composition in UML Models	201
<i>Eunjee Song and Nathan V. Roberts</i>	
A New Method for Measuring Single Event Effect Susceptibility of L1 Cache Unit	203
<i>Yongbin Zhou, Jun Yang, and Yueke Wang</i>	
Detecting Emotions and Dangerous Actions for Better Human-System Team Working	205
<i>Shuichi Fukuda</i>	
Estimation of the Change Point for Failure-Censored Data via Bayesian Information Criterion	207
<i>Nobuyuki Tamura, Tetsushi Yuge, and Shigeru Yanagi</i>	
Dependable Mechatronic Products: Closing the Intelligence Gap	209
<i>Nico Wolf and Jan C. Aurich</i>	

System-Bus Fault Injection Framework in SystemC Design Platform	211
<i>Kun-Chun Chang, Yi-Chinag Wang, Chung-Hsien Hsu, Kuen-Long Leu, and Yung-Yuan Chen</i>	
Fast Abstract (4)	
Strategic Usage of Test Case Generation by Combining Two Test Case Generation Approaches	213
<i>Haruka Nakao and Robert Eschbach</i>	
An Experimental Study on Latch Up Failure of CMOS LSI	215
<i>Hideo Kohinata, Masayuki Arai, and Satoshi Fukumoto</i>	
Conception for Integrated Availability in Design for the Nuclear Systems	217
<i>Vasile Anghel</i>	
An Estimation Model of Vulnerability for Embedded Microprocessors	224
<i>Yung-Yuan Chen, Shu-Hao Hsu, and Kuen-Long Leu</i>	
Early Reliability Prediction: An Approach to Software Reliability Assessment in Open Software Adoption Stage	226
<i>Wangbong Lee, Boo-Geum Jung, and Jongmoon Baik</i>	
Automation of Look-Up Tables for System Integrity Protection Systems in Taiwan Power System	228
<i>Shih-En Chien, I-Ta Cherng, and Chih-Wen Liu</i>	
Face Detection Based on Skin Color Segmentation and SVM Classification	230
<i>Hwei-Jen Lin, Shwu-Huey Yen, Jih-Pin Yeh, and Meng-Ju Lin</i>	
Author Index	232